

TECNAI

Tecnai T-12 TEM

- Nanometer level imaging and elemental analysis
- Variable accelerating voltage can be customized to suit sample sensitivity



Dramatic bend-contour lines highlight the orientation of single crystal borides.



Kikuchi lines point to specific crystal directions in this convergent beam diffraction pattern (CBED) of CrNb.



CAMMA
Center for Advanced Microscopy and Materials Analysis

ThermoFisher
SCIENTIFIC